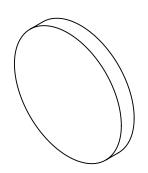
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 408 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 390nm @ 0° AOI T(abs): =50% FOR 400±4nm @ 0° AOI

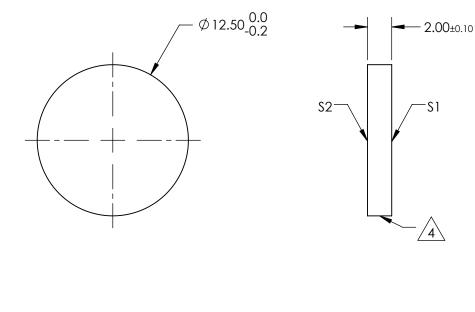
S2:SINGLE LAYER MgF2

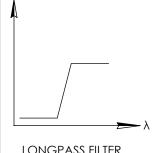
4. FINE GRIND SURFACE

- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT









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LONGPASS FILTER						Edmund Optic	C ®
REV A	S1	S2					, 3
SHAPE	PLANO	PLANO				Ø12.5mm, 400nm, HIGH PERFORMAN	ICF
SURFACE QUALITY	40-20	40-20	THIRD ANGLE		TITLE	LONGPASS FILTER	
CLEAR APERTURE	>80%	>80%					CUEFT
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN	mm	DWG NO	62974	Sheet 1 Of 1

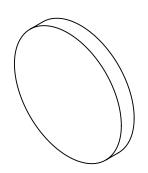
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 458 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 440nm @ 0° AOI T(abs): =50% FOR 450±4.5nm @ 0° AOI

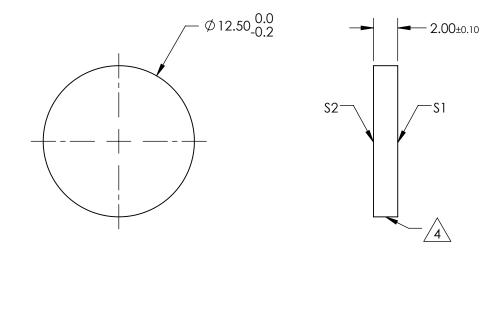
S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE

- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT







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LONGPASS FILTER					Edmund Optics [®]
REV A	S1	S2			
SHAPE	PLANO	PLANO			Ø12.5mm, 450nm, HIGH PERFORMANCE
SURFACE QUALITY	40-20	40-20		TITLE	LONGPASS FILTER
CLEAR APERTURE	>80%	>80%			
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN mm	DWG NO	62975 SHEET 1 OF 1

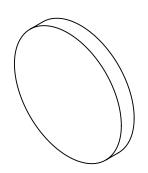
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 508 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 490nm @ 0° AOI T(abs): =50% FOR 500±5nm @ 0° AOI

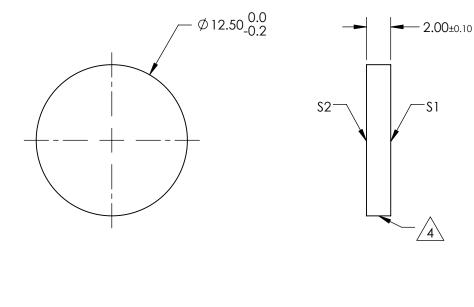
S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE

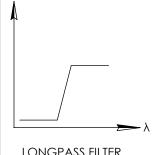
- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT







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						Edmund Optics	c ®
REV A	S1	S2					3
SHAPE	PLANO	PLANO				Ø12.5mm, 500nm, HIGH PERFORMAN	CF
SURFACE QUALITY	40-20	40-20			TITLE	LONGPASS FILTER	
CLEAR APERTURE	>80%	>80%		1			CLIEFT
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN	mm	DWG NO	62976	Sheet 1 Of 1

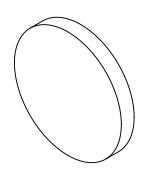
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 560 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 539nm @ 0° AOI T(abs): =50% FOR 550±5.5nm @ 0° AOI

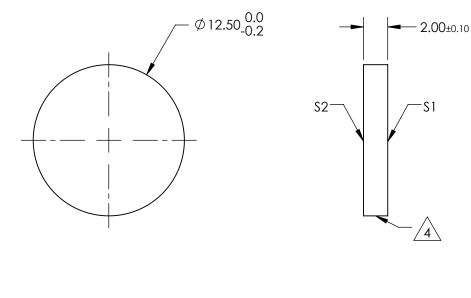
S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE

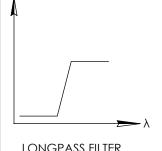
- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT







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LONGINGSTIELER			_			Edmund Optic	C ®
REV A	S1	\$2					, 3
SHAPE	PLANO	PLANO				Ø12.5mm, 550nm, HIGH PERFORMAN	ICF
SURFACE QUALITY	40-20	40-20	THIRD ANGLE	$\rightarrow \bigcirc \mid$	TITLE	LONGPASS FILTER	, OL
CLEAR APERTURE	>80%	>80%	 				
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN r	mm	DWG NO	62977	Sheet 1 Of 1

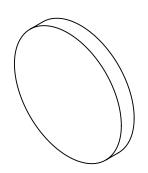
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 610 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 588nm @ 0° AOI T(abs): =50% FOR 600±6nm @ 0° AOI

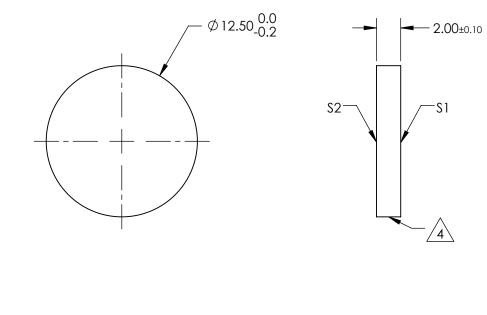
S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE

- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT







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LONGPASS FILTER					Edmund Optic	°C®
REV A	S1	S2				5
SHAPE	PLANO	PLANO			Ø12.5mm, 600nm, HIGH PERFORMAN	JCF
SURFACE QUALITY	40-20	40-20		TITLE	LONGPASS FILTER	UCL
CLEAR APERTURE	>80%	>80%				CUEET
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN mm	DWG NO	62978	Sheet 1 Of 1

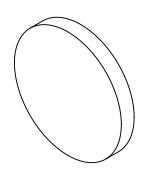
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 660 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 637nm @ 0° AOI T(abs): =50% FOR 650±6.5nm @ 0° AOI

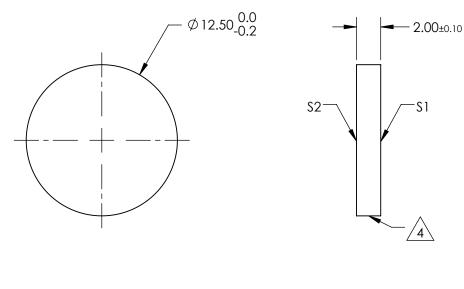
S2:SINGLE LAYER MgF2

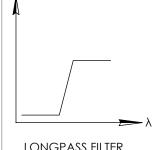
4. FINE GRIND SURFACE

- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT









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LONGPASS FILTER						Edmund Optics	C ®
REV A	S1	S2					3
SHAPE	PLANO	PLANO				Ø12.5mm, 650nm, HIGH PERFORMAN	CF
SURFACE QUALITY	40-20	40-20			TITLE	LONGPASS FILTER	
CLEAR APERTURE	>80%	>80%		1			CLIEFT
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN	mm	DWG NO	62979	Sheet 1 Of 1

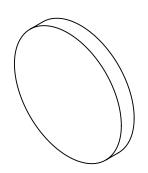
- 1. SUBSTRATE
- 2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN 5 arcsec
- COATING (APPLY ACROSS COATING APERTURE) S1: HARD DIELECTRIC SPUTTERED T(avg): ≥91% FROM 765 - 1650nm @ 0° AOI T(avg): ≤0.01% FROM 200 - 735nm @ 0° AOI T(abs): =50% FOR 750±7.5nm @ 0° AOI

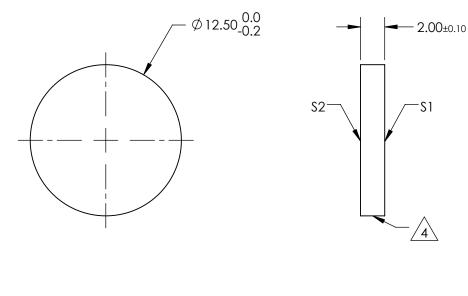
S2:SINGLE LAYER MgF2

4. FINE GRIND SURFACE

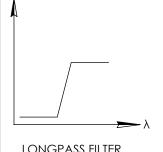
- 5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. TRANSMITTED WAVEFRONT DISTORTION, RMS: ≤λ/4 @ 633nm
- 7. ROHS COMPLIANT







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LONGINGSTILLER						Edmund Optic	C®
REV A	S1	S2					<u>Э</u>
SHAPE	PLANO	PLANO				Ø12.5mm, 750nm, HIGH PERFORMAN	CF
SURFACE QUALITY	40-20	40-20	THIRD ANGLE PROJECTION	$\bigcirc \bigcirc$	TITLE	LONGPASS FILTER	01
CLEAR APERTURE	>80%	>80%		1			SHEET
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN	mm	DWG NO	66226	1 OF 1